

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/026,427	CHOI ET AL.	
Examiner	Art Unit	
Shick C. Hom	2666	

	SEARCHED						
Class	Subclass	Date	Examiner				
	updated search	2/1/2006	SH				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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